Atty.	Docket	No.	RDRT	.1027-2
Appl.	. No.			

Claim 11 (cancelled)

Claim 12 (cancelled)

This listing of claims will replace all prior versions, and listings, of claims in the application.

Listing of Claims Claim 1 (cancelled) Claim 2 (cancelled) Claim 3 (cancelled) Claim 4 (cancelled) Claim 5 (cancelled) Claim 6 (cancelled) Claim 7 (cancelled) Claim 8 (cancelled) Claim 9 (cancelled) Claim 10 (cancelled)

- Claim 13 (currently amended): A method for constructing an inductive write element structure for use in a magnetic data recording system, comprising the steps of:
 - [[a.]] forming a first magnetic pole of a magnetic material;
 - [[b.]] depositing a first insulation layer;
 - [[c.]] depositing a layer of dielectric write gap material;
 - [[d.]] forming an electrically conductive coil;
 - [[e.]] depositing a second insulation layer;
 - [[f.]] curing said second insulation layer;
 - [[g.]] sputter depositing a thin layer of high magnetic moment material;
 - [[h.]] patterning a second pole;
 - [[i.]] plating a magnetic material in the pattern of said second pole; and
 - [[j.]] performing a first ion milling process, to remove at least a portion of the sputtered, high magnetic moment material not covered by the plated second pole.
- Claim 14 (currently amended) A method for constructing an inductive write element as recited in

 The method of claim 13, further comprising, after forming the first magnetic pole the steps

 of:
 - [[a.]] sputter depositing a layer of a high magnetic moment material onto said first pole;
 - [[b.]] masking the high magnetic moment material sputter deposited onto first pole in a pattern corresponding to a pedestal to be formed on an end of the first pole; and
 - [[c.]] etching to remove said sputter deposited high magnetic moment material not covered by said mask to form said pedestal.

Claim 15 (currently amended) A method for constructing an inductive write element as recited in

The method of claim 14, further comprising the steps of:

- [[a.]] depositing a mask on said plated magnetic material forming said second pole, said mask being disposed at an end of said second pole;
- [[b.]] performing a second ion milling process to remove a portion of said second pole at said end;
- [[c.]] performing a reactive ion etching process to remove a portion of said dielectric write gap material layer; and
- [[d.]] performing a third ion milling process to remove a material from said pedestal.

Claim 16 (currently amended) A method for constructing an inductive write element as recited in The method of claim 14, further comprising, following depositing the first insulation layer, the step of polishing said first insulation layer using a chemical mechanical polishing process.

Claim 17 (currently amended) A method for constructing an inductive write element as recited in The method of claim 13 wherein sputter depositing the [[said]] high magnetic moment material is sputter deposited comprises sputter depositing FeXN, X being selected from the group of materials consisting of Rh, Ta, Al, Ti, and Zr.

Claim 18 (currently amended) A method for constructing an inductive write element as recited in The method of claim 17 wherein sputter depositing the [[said]] high magnetic moment material comprises sputtering a lamina of FeXn and further comprises depositing a lamina [[includes lamination layers]] of a cobalt based ferromagnetic amorphous alloy.

Claim 19 (currently amended) A method for constructing an inductive write element as recited in The method of claim 18 wherein depositing the cobalt based ferromagnetic amorphous alloy comprises depositing [[said lamination layers are]] Co₉₀Zr₉Cr.

Claim 20 (cancelled)

Claim 21 (new): The method of claim 17 wherein depositing FeXn comprises depositing Rh.

Claim 22 (new): The method of claim 17 wherein depositing FeXn comprises depositing Ta.

Claim 23 (new): The method of claim 17 wherein depositing FeXn comprises depositing Al.

Claim 24 (new): The method of claim 17 wherein depositing FeXn comprises depositing Ti.

Claim 25 (new): The method of claim 17 wherein depositing FeXn comprises depositing Zr.

Claim 26 (new): The method of claim 13 wherein plating the second pole magnetic material comprises plating a Ni-Fe alloy.

Claim 27 (new): The method of claim 13 wherein plating the second pole magnetic material comprises plating to a material thickness about 2um.

Claim 28 (new): The method of claim 14 wherein sputter depositing the high magnetic moment material comprises sputter depositing FeXN, X being selected from the group of materials consisting of Rh, Ta, Al, Ti, and Zr.

Claim 29 (new): The method of claim 14 wherein sputter depositing the high magnetic moment material comprises sputter depositing a lamina of FeXn, and further comprises depositing a lamina of a cobalt based ferromagnetic amorphous alloy.

Claim 30 (new): The method of claim 14 wherein sputter depositing the high magnetic moment material comprises sputter depositing a lamina of FeXn, and further comprises depositing a lamina of Co₉₀Zr₉Cr.

Claim 31 (new): The method of claim 14 wherein sputter depositing the high magnetic moment material onto the first pole comprises sputter depositing Rh.

Claim 32 (new): The method of claim 14 wherein sputter depositing the high magnetic moment material onto the first pole comprises sputter depositing Ta.

Claim 33 (new): The method of claim 14 wherein sputter depositing the high magnetic moment material onto the first pole comprises sputter depositing Al.

Claim 34 (new): The method of claim 14 wherein sputter depositing the high magnetic moment material onto the first pole comprises sputter depositing Ti.

Claim 35 (new): The method of claim 14 wherein sputter depositing the high magnetic moment material onto the first pole comprises sputter depositing Zr.

Claim 36 (new): The method of claim 14 wherein sputter depositing the high magnetic moment material comprises depositing at least one lamina of a high magnetic moment material and at least one lamina of a non-magnetic, dielectric material.

Claim 37 (new): The method of claim 14 wherein sputter depositing the high magnetic moment material comprises depositing at least one lamina of FeXN, wherein X is selected from the group of materials consisting of Rh, Ta, Al, Ti and Zr, and at least one lamina of a non-magnetic, dielectric material.

Claim 38 (new): The method of claim 14 wherein sputter depositing the high magnetic moment material comprises depositing at least one lamina of a high magnetic moment material and at least one lamina of a cobalt based amorphous ferromagnetic alloy.

Claim 39 (new): The method of claim 14 wherein sputter depositing the high magnetic moment material comprises depositing at least one lamina of a high magnetic moment material and at least one lamina of Co₉₀Zr₉Cr.

Claim 40 (new): The method of claim 14 wherein sputter depositing the high magnetic moment material onto the first pole comprises sputter depositing FeXN, X being selected from the group of materials consisting of Rh, Ta, Al, Ti, and Zr.

Claim 41 (new): The method of claim 40 wherein sputter depositing the high magnetic moment material onto the first pole comprises sputter depositing a lamina of FeXn, and further comprises depositing a lamina of a cobalt based ferromagnetic amorphous alloy.

Claim 42 (new): The method of claim 40 wherein sputter depositing the high magnetic moment material onto the first pole further comprises depositing a lamina of Co₉₀Zr₉Cr.

Claim 43 (new): The method of claim 40 wherein sputter depositing the high magnetic moment material onto the first pole comprises depositing Rh.

Claim 44 (new): The method of claim 40 wherein sputter depositing the high magnetic moment material onto the first pole comprises depositing Ta.

Claim 45 (new): The method of claim 40 wherein sputter depositing the high magnetic moment material onto the first pole comprises depositing Al.

Claim 46 (new): The method of claim 40 wherein sputter depositing the high magnetic moment material onto the first pole comprises depositing Ti.

Claim 47 (new): The method of claim 40 wherein sputter depositing the high magnetic moment material onto the first pole comprises depositing Zr.

Claim 48 (new): The method of claim 14 wherein said pedestal comprises forming a laminate comprising at least one lamina of a high magnetic moment material and at least one lamina of a non-magnetic, dielectric material.

Claim 49 (new): The method of claim 14 wherein said pedestal comprises forming a laminate comprising at least one lamina of FeXN, wherein X is selected from the group of materials consisting of Rh, Ta, Al, Ti and Zr, and at least one lamina of a non-magnetic, dielectric material.

Claim 50 (new): The method of claim 14 wherein said pedestal comprises forming a laminate comprising at least one lamina of a high magnetic moment material and at least one lamina of a cobalt based amorphous ferromagnetic alloy.

Claim 51 (new): The method of claim 14 wherein said pedestal comprises forming a laminate comprising at least one lamina of a high magnetic moment material and at least one lamina of Co₉₀Zr₉Cr.